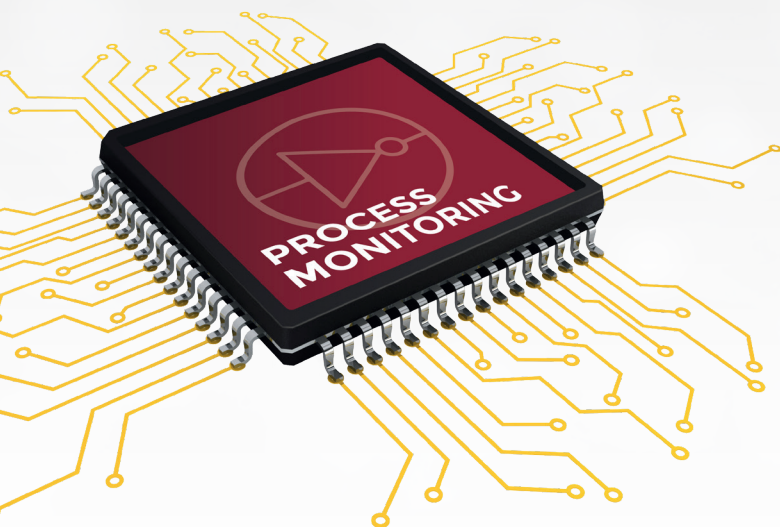


## Moortec Embedded Process Monitor IP

Moortec Semiconductor provides Embedded Process Monitor IP for your advanced node System on Chip (SoC) at 28nm and FinFET. Highest accuracy for best device performance optimisation.



### Features:

- Support for custom delay chain structures
- Digital interface options (including AMBA APB, SPI, I2C and IEEE P1500)
- Signature Response on Demand
- Scan-path Inserted
- Fault coverage and test options
- Created using standard digital process layers
- Small size
- Measurement of multiple device types
- Ability to connect VDDA to VSS when not using thick oxide delay chain

### Deliverables:

- GDSII
- LEF (Abstract) view
- Liberty timing files
- LVS netlist
- Verilog model

### Applications:

- Energy (DVFS) Optimisation
- Delay loop speed characterisation
- Critical Path Analysis
- Critical Voltage Analysis
- Age Monitoring

### Silicon characterisation and qualification:

- Stress based JEDEC HTOL testing
- Accurately monitoring during device characterisation

### Digital interface provides:

- Simplified integration with no shielded analogue signals to route
- Easily addressable sensor instances

### Interfacing options:

- AMBA APB interface available
- IEEE P1500 interface available

### Available on:

- TSMC
- Global Foundries
- SMIC
- UMC

